Receipt date: 09/15/2006

10592971 - GAP16 Rec'd PCT/PTO 15 SEP 2006

Based on Form	PTO-1449				ATTY. DOCKET NO. SERIAL NO.					
(3/90) LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)					930086-2038	TO BE ASSIGNED				
					APPLICANT Heon Jin CHOI, et al.					
					FILING DATE TO BE ASSIGN	GROUP TO BE ASSIGNED				
				U.S. PATE	NT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME		CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
	AA	2003/0052006 A1	03/20/03	Noca	Noca et al.		450			
	AB	6,288,390 B1	09/11/01	Siuzdak et al.		250	288			
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		FOREIGN PATENT DOCUMENTS DOCUMENT NUMBER DATE COUNTRY CLASS SUBCLASS TRANSLATIO						LATION		
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	AG	08-315633	11/29/96	Japan				Abst.		
	AH	10-2001-0081780	06/25/03	Korea				Abst.		
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	AK									
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.) Min-Jung Kang, et al., "Application of Automated Matrix-Assisted Laser Desorption/Ionization Time-of									ne-of-	
	AL	Flight Mass Spectrometry For The Measurement Of Enzyme Activities", Rapid Commun. Mass Spectro 2001; 15: pp. 1327-1333.								
	AM		Jing Wei, et al., "Desorption-Ionization Mass Spectrometry on Porous Silicon", (1999) Nature, Vol. 399,							
	AN	Warren G. Lewis, et al., "Desorption/Ionization on Silicon (DIOS) Mass Spectrometry: Background and Applications, International Journal of Mass Spectrometry, 226 (2003) pp. 107-116								
<u> </u>	AO	Justin C. Johnson, et al., "Single Gallium Nitride Nanowire Lasers, Nature Materials, Vol. 1, October								
			2002) pp. 106-110. Vladimir E. Frankevich, "Role of Electrons in Laser Desorption/Ionization Mass Spectrometry",							
	AP	Analytical Che	Analytical Chemistry, Vol. 75 No. 22, November 15, 2003, pp. 6063-6067.							
	AQ	Press, 1996, p	G/ Suizdak, 1. Ion Sources and Sample Introduction, In: Mass Spectroscopy for Biotechnology, Academic Press, 1996, p. 13.							
	AR	J.M. Bermond	J.M. Bermond, et al. Sur. Sci. 42 (1974) p. 306							
	AS									
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EXAMINER	/Hanway Chang/ Date considered 02/25/2009									
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